

DATA SHEET

NEC**MOS FIELD EFFECT TRANSISTOR
NP32N055HLE, NP32N055ILE****SWITCHING
N-CHANNEL POWER MOS FET
INDUSTRIAL USE****DESCRIPTION**

These products are N-channel MOS Field Effect Transistor designed for high current switching applications.

FEATURES

- Channel temperature 175 degree rated
- Super low on-state resistance
 $R_{DS(on)1} = 24 \text{ m}\Omega \text{ MAX. (} V_{GS} = 10 \text{ V, } I_D = 16 \text{ A)}$
 $R_{DS(on)2} = 29 \text{ m}\Omega \text{ MAX. (} V_{GS} = 5.0 \text{ V, } I_D = 16 \text{ A)}$
- Low C_{iss} : $C_{iss} = 1300 \text{ pF TYP.}$
- Built-in gate protection diode

ORDERING INFORMATION

PART NUMBER	PACKAGE
NP32N055HLE	TO-251
NP32N055ILE	TO-252

ABSOLUTE MAXIMUM RATINGS (T_A = 25°C)

Drain to Source Voltage	V_{DSS}	55	V
Gate to Source Voltage	V_{GSS}	±20	V
Drain Current (DC)	$I_{D(DC)}$	±32	A
Drain Current (Pulse) ^{Note1}	$I_{D(pulse)}$	±100	A
Total Power Dissipation (T _A = 25°C)	P_T	1.2	W
Total Power Dissipation (T _C = 25°C)	P_T	66	W
Single Avalanche Current ^{Note2}	I_{AS}	28 / 21 / 8	A
Single Avalanche Energy ^{Note2}	E_{AS}	7.8 / 44 / 64	mJ
Channel Temperature	T_{ch}	175	°C
Storage Temperature	T_{stg}	-55 to +175	°C

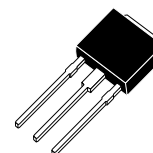
Notes 1. $PW \leq 10 \mu s$, Duty cycle $\leq 1 \%$

2. Starting $T_{ch} = 25^\circ\text{C}$, $R_G = 25 \Omega$, $V_{GS} = 20 \text{ V} \rightarrow 0 \text{ V}$ (See Figure 4.)

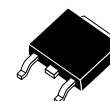
THERMAL RESISTANCE

Channel to Case	$R_{th(ch-C)}$	2.27	°C/W
Channel to Ambient	$R_{th(ch-A)}$	125	°C/W

(TO-251)



(TO-252)

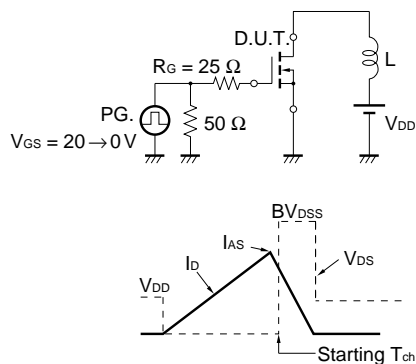


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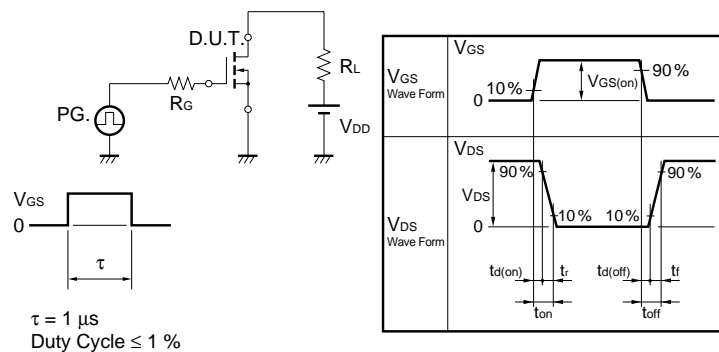
ELECTRICAL CHARACTERISTICS (T_A = 25 °C)

CHARACTERISTICS	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Drain to Source On-state Resistance	R _{DS(on)1}	V _{GS} = 10 V, I _D = 16 A		19	24	mΩ
	R _{DS(on)2}	V _{GS} = 5.0 V, I _D = 16 A		22	29	mΩ
	R _{DS(on)3}	V _{GS} = 4.5 V, I _D = 16 A		24	33	mΩ
Gate to Source Threshold Voltage	V _{GS(th)}	V _{DS} = V _{GS} , I _D = 250 μA	1.5	2	2.5	V
Forward Transfer Admittance	y _{fs}	V _{DS} = 10 V, I _D = 16 A	8	16		S
Drain Leakage Current	I _{DSS}	V _{DS} = 55 V, V _{GS} = 0 V			10	μA
Gate to Source Leakage Current	I _{GSS}	V _{GS} = ±20 V, V _{DS} = 0 V			±10	μA
Input Capacitance	C _{iss}	V _{DS} = 25 V, V _{GS} = 0 V, f = 1 MHz		1300	2000	pF
Output Capacitance	C _{oss}			180	270	pF
Reverse Transfer Capacitance	C _{rss}			90	160	pF
Turn-on Delay Time	t _{d(on)}	I _D = 16 A, V _{GS(on)} = 10 V, V _{DD} = 28 V, R _G = 1 Ω		14	31	ns
Rise Time	t _r			8	20	ns
Turn-off Delay Time	t _{d(off)}			40	81	ns
Fall Time	t _f			7.4	19	ns
Total Gate Charge	Q _{G1}	I _D = 32 A, V _{DD} = 44 V, V _{GS} = 10 V		27	41	nC
	Q _{G2}		I _D = 32 A, V _{DD} = 44 V, V _{GS} = 5.0 V		15	23
Gate to Source Charge	Q _{GS}			5		nC
Gate to Drain Charge	Q _{GD}			9		nC
Body Diode Forward Voltage	V _{F(S-D)}	I _F = 32 A, V _{GS} = 0 V		1.0		V
Reverse Recovery Time	t _{rr}	I _F = 32 A, V _{GS} = 0 V, di/dt = 100 A/μs		41		ns
Reverse Recovery Charge	Q _{rr}			58		nC

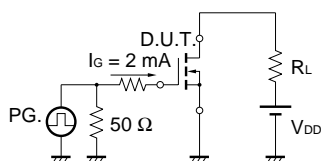
TEST CIRCUIT 1 AVALANCHE CAPABILITY



TEST CIRCUIT 2 SWITCHING TIME



TEST CIRCUIT 3 GATE CHARGE



TYPICAL CHARACTERISTICS (T_A = 25 °C)

Figure1. DERATING FACTOR OF FORWARD BIAS SAFE OPERATING AREA

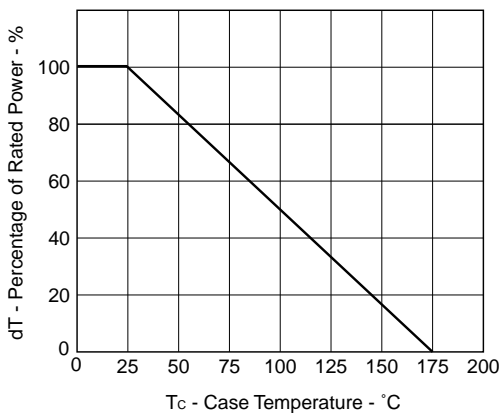
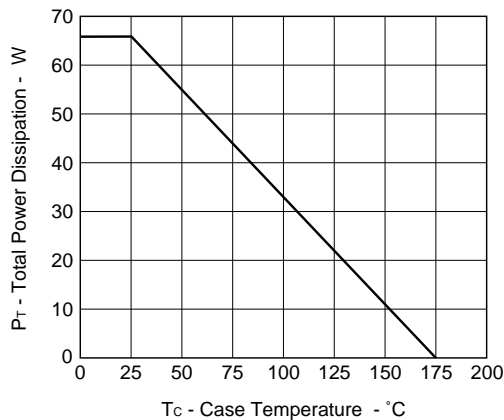


Figure2. TOTAL POWER DISSIPATION vs. CASE TEMPERATURE



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Figure3. FORWARD BIAS SAFE OPERATING AREA

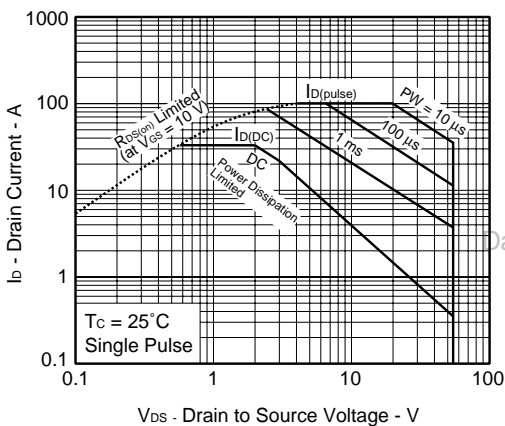


Figure4. SINGLE AVALANCHE ENERGY DERATING FACTOR

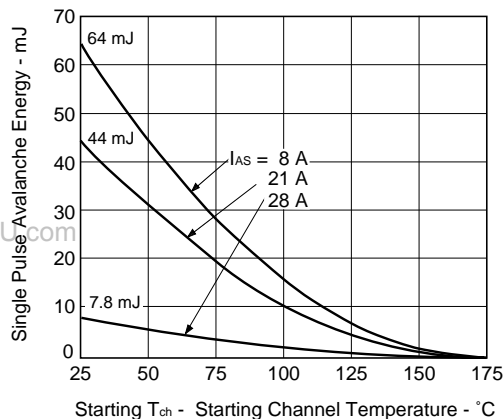
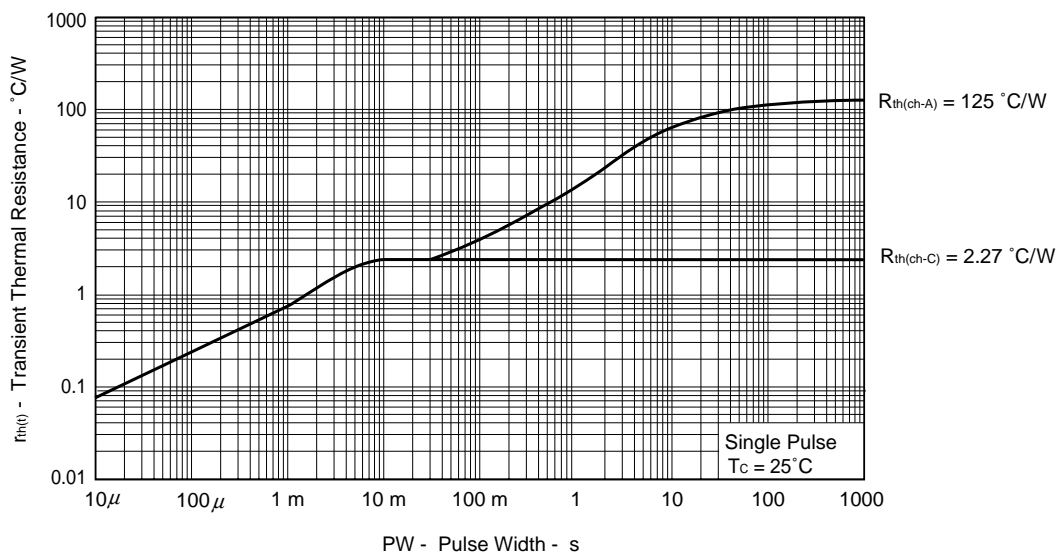


Figure5. TRANSIENT THERMAL RESISTANCE vs. PULSE WIDTH



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Figure6. FORWARD TRANSFER CHARACTERISTICS

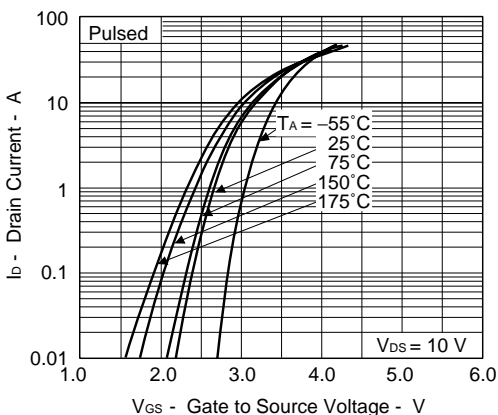


Figure7. DRAIN CURRENT vs. DRAIN TO SOURCE VOLTAGE

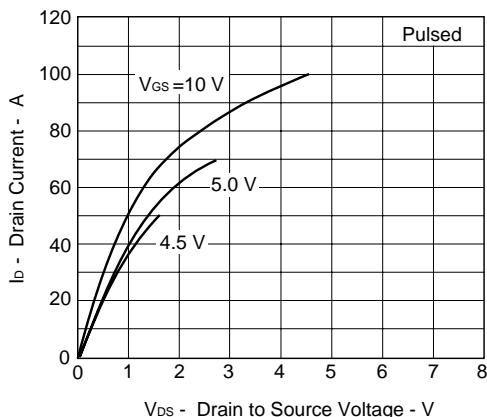


Figure8. FORWARD TRANSFER ADMITTANCE vs. DRAIN CURRENT

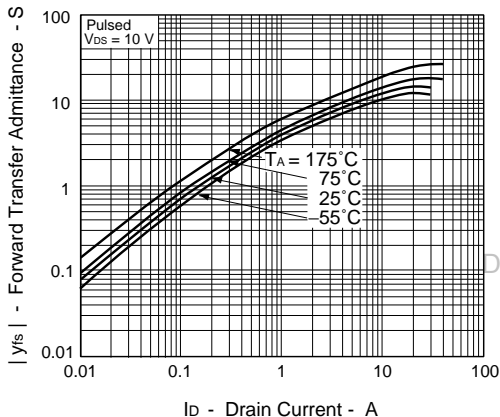


Figure9. DRAIN TO SOURCE ON-STATE RESISTANCE vs. GATE TO SOURCE VOLTAGE

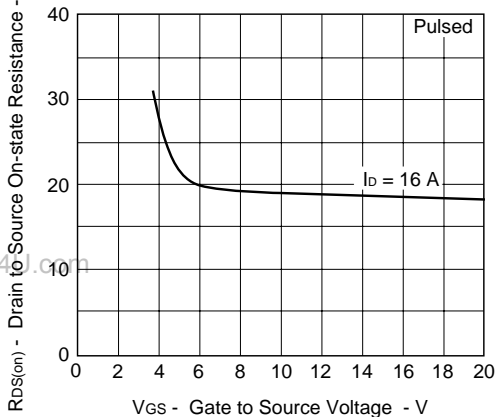


Figure10. DRAIN TO SOURCE ON-STATE RESISTANCE vs. DRAIN CURRENT

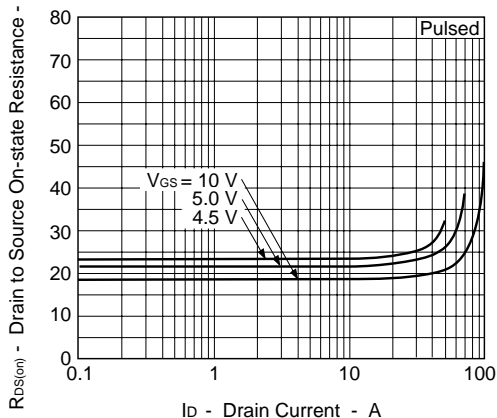


Figure11. GATE TO SOURCE THRESHOLD VOLTAGE vs. CHANNEL TEMPERATURE

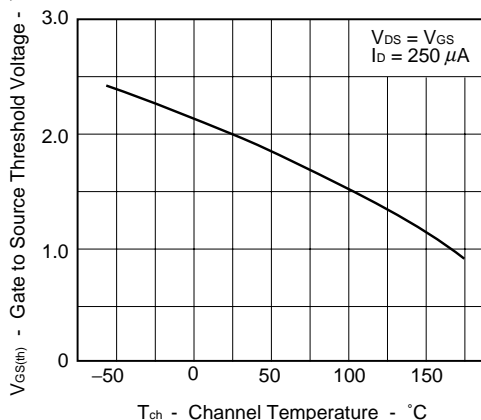


Figure12. DRAIN TO SOURCE ON-STATE RESISTANCE vs. CHANNEL TEMPERATURE

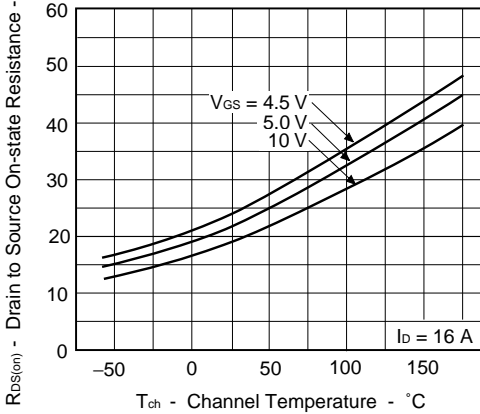


Figure13. SOURCE TO DRAIN DIODE FORWARD VOLTAGE

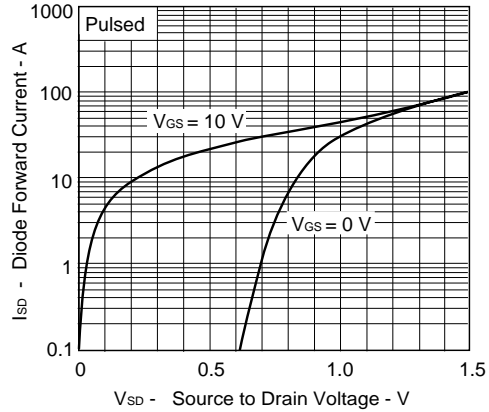


Figure14. CAPACITANCE vs. DRAIN TO SOURCE VOLTAGE

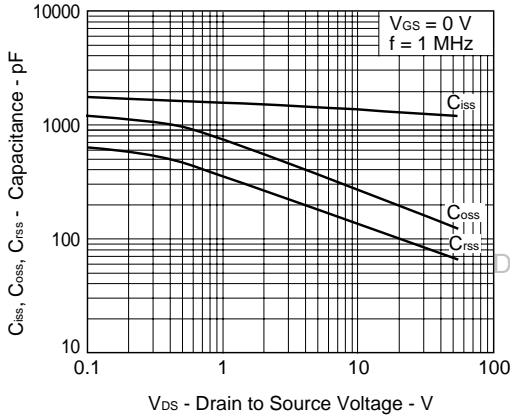


Figure15. SWITCHING CHARACTERISTICS

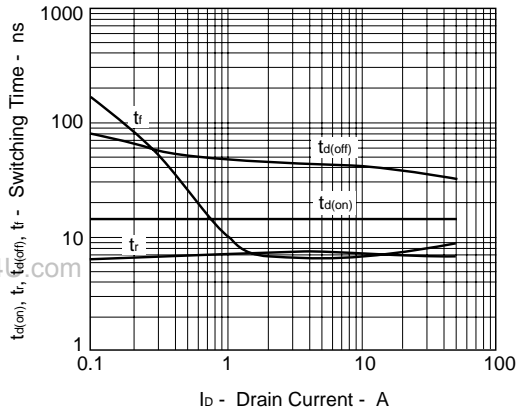


Figure16. REVERSE RECOVERY TIME vs. DRAIN CURRENT

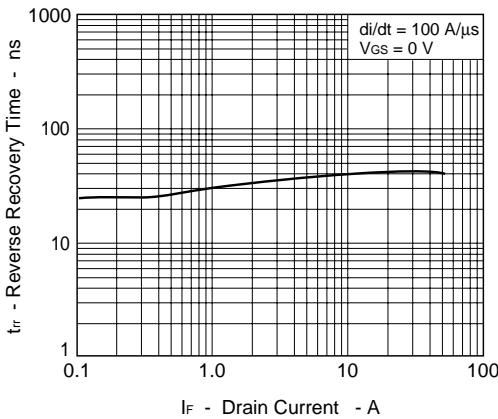
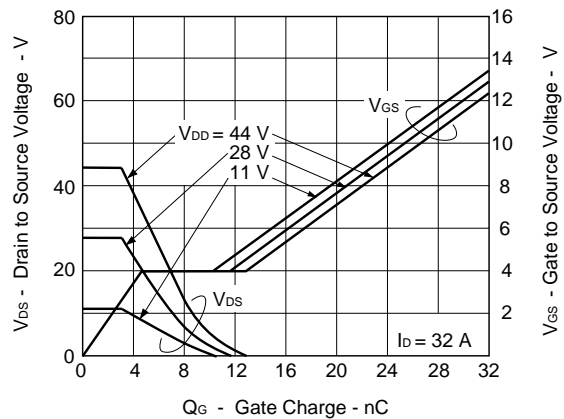


Figure17. DYNAMIC INPUT/OUTPUT CHARACTERISTICS



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